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Effects of Length Dispersity and Film Fabrication on the Sheet Resistance of Copper Nanowire Transparent Conductors

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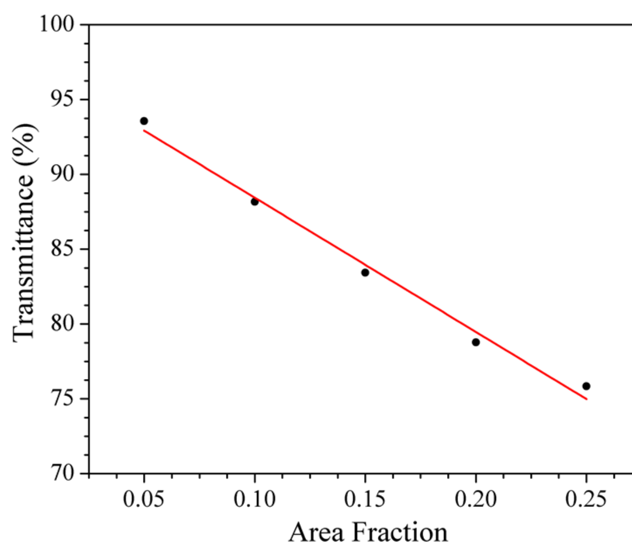

Figure S1: Calibration curve for the determination of Area Fraction from %T measurements of Cu NW films on PET. A linear fit was obtained using OriginPro 8.1. The fit details are as follows:

	Intercept		Slope		Statistics
	Value	Standard Error	Value	Standard Error	Adj. R-Square
%T	97.41234	0.84752	-89.71336	5.11071	0.98714